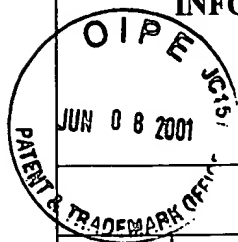


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INFORMATION DISCLOSURE STATEMENT

BY APPLICANT

Docket: 1011-54375

App: 09/620,021

Applicant: Rajski et al.

Filed: July 20, 2000

Art Unit: ~~2858~~ 2133

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Init.*	Number	Date	Name	Class	Sub	Filed
PMC	3,614,400	Oct-71	Farnett	1	1	
	3,700,869	Oct-72	Low et al.	1	1	
	4,503,537	Mar-85	McAnney	1	1	
	4,687,988	Aug-87	Eichelberger et al.	1	1	
	4,754,215	Jun-98	Kawai	1	1	
	4,785,410	Nov-88	Hamatsu et al.	1	1	
	4,801,870	Jan-89	Eichelberger et al.	1	1	
	4,860,236	Aug-89	McLeod et al.	1	1	
	4,959,832	Sep-90	Bardell, Jr.	1	1	
	4,974,184	Nov-98	Avra	1	1	
	5,090,035	Feb-92	Murase	1	1	
	5,138,619	08/11/92	Fasang et al.	1	1	
	5,173,906	12/22/1992	Dreibelbis et al.	1	1	
	5,268,949	Dec-93	Watanabe	1	1	
	5,301,199	04/05/1994	Ikenaga et al.	1	1	
	5,325,367	Jun-94	Dekker et al.	1	1	
PMC	5,369,648	Nov-94	Nelson	1	1	

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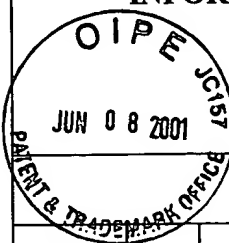
**INFORMATION DISCLOSURE
STATEMENT**
BY APPLICANT

Docket: 1011-54375

App: 09/620,021

Applicant: Rajski et al.

Filed: July 20, 2000

Art Unit: ~~2858~~ 2133
U.S. PATENT DOCUMENTS

Init.*	Number	Date	Name	Class	Sub	Filed
<i>me</i>	5,394,405	Feb-95	Savir	_____	_____	
	5,412,665	May-95	Gruodis et al.	_____	_____	
	5,414,716	May-95	Bershteyn	_____	_____	
	5,446,683	Aug-95	Mullen et al.	_____	_____	
	5,450,414	Sep-95	Lin	_____	_____	
	5,574,733	Nov-96	Kim	_____	_____	
	5,586,125	12/17/1996	Warner	_____	_____	
	5,612,963	Mar-97	Koenemann et al.	_____	_____	
	5,631,913	May-97	Maeda	_____	_____	
	5,694,402	12/02/1997	Butler et al.	_____	_____	
	5,719,913	Feb-98	Maeno	_____	_____	
	5,748,497	May-98	Scott et al.	_____	_____	
	5,790,562	08/04/98	Murray et al.	_____	_____	
	5,790,626	Aug-98	Johnson et al	_____	_____	
	5,831,992	Nov-98	Wu	_____	_____	
	5,899,961	May-99	Sundermann	_____	_____	
<i>PC</i>	5,974,433	Oct-99	Currie	_____	_____	

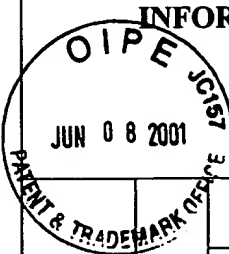
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U.S. PATENT DOCUMENTS

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT		Docket: 1011-54375	App: 09/620,021
		Applicant: Rajski et al.	
		Filed: July 20, 2000	Art Unit: 2858
		J. Rajski, J. Tyszer, N. Zacharia, "Test Data Decompression for Multiple Scan Designs with Boundary Scan," IEEE Transactions on Computers, Vol. 47, No. 11, November 1998	
		J. Rajski and J. Tyszer, "Design of Phase Shifters for BIST Applications", <i>Proc. VLSI Test Symposium</i> , pp. 218-224, 1998.	
		J. Rajski, N. Tamarapalli, J. Tyszer, "Automated Synthesis of Large Phase Shifters for Built-In Self-Test," International Test Conference, Paper 41.1, pp. 1047-1056, IEEE 1998	
		Venkataraman, Rajski, Hellebrand, and Tarnick, "An Efficient BIST Scheme Based on Reseeding of Multiple Polynomial Linear Feedback Shift Registers", pp. 572-577, 1993 IEEE	

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	09/713,662	11/15/2000	Rajski et al.			
	09/713,664	11/15/2000	Rajski et al.			
	09/619,988	07/20/2000	Rajski et al.			
	09/620,023	07/20/2000	Rajski et al.			
	09/619,985	07/20/2000	Rajski et al.			

Note: These US patent applications had not been considered by Examiner because the US patent applications can't be (considered) listed as Prior Art for a suggestion these copending US patent applications should be listed in the specification.

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INFORMATION DISCLOSURE STATEMENT

BY APPLICANT

Docket: 1011-54375

App: 09/620,021

Applicant: Rajski et al.

Filed: July 20, 2000

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	Number	Date	Name	Class	Sub	Filed
pmc	5,991,898	11/23/1999	Rajski et al.			
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	6,006,349	Dec-99	Fujisaki			
	6,072,823	Jun-00	Takakusaki			
pmc	6,141,669	Oct-00	Carleton			

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pmc		P.H. Bardell, "Design Considerations for Parallel Pseudorandom Pattern Generators", Journal of Electronic Testing: Theory and Applications, 1,73-87 (1990)
pmc		I. Hamzaoglu, J. Patel, "Reducing Test Application Time for Full Scan Embedded Cores," Center for Reliable & High-Performance Computing, University of Illinois, Urbana, IL., 1999 IEEE
pmc		S. Hellebrand, J. Rajski, S. Tarnick, S. Venkataraman, B. Courtois, "Built-in Test for Circuits With Scan Based on Reseeding of Multiple Polynomial Linear Feedback Shift Registers", <i>IEEE Trans. On Computers</i> , vol. C-44, pp. 223-233, 1995.
pmc		S. Hellebrand, B. Reeb, S. Tarnick, H-J Wunderlich, "Pattern Generation for a Deterministic BIST Scheme", pp. 88-94 1995 IEEE
pmc		B. Koenemann c/o IBM Corp., B56/901, "LFSR-Coded Test Patterns for Scan Designs", <i>Proceedings of European Test Conference</i> , pp. 237-242, 1991.

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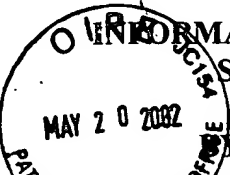
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pmc		J. Rajski, J. Tyszer, N. Zacharia, "Decompression of Test Data Using Variable-Length Seed LFSRs" Microelectronics and Computer Systems Laboratory, McGill University, Montreal, Canada, 1995 IEEE
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RFS:dsh 05/06/02 1011-54375 Document in ProLaw

	Docket: 1011-54375	App: 09/620,021
	Applicant: Rajski et al.	
	Filed: July 20, 2000	Art Unit: 2058 2133

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pmc	4,513,418	4/1985	Bardell, Jr. et al.			
	4,602,210	7/1986	Fasang et al.			
	5,905,986	5/1999	Rohrbaugh et al.			
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	6,158,032	12/2000	Currier et al.			
pmc	6,300,885	10/2001	Davenport et al.			

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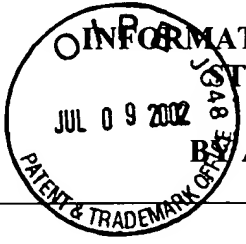
DATE *9/26/02*

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#7

		Docket: 1011-54375	App: 09/620,021
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OTHER DOCUMENTS			
<i>me</i>			Bershteyn, M., "Calculation of Multiple Sets of Weights for Weighted Random Testing," International Test Conference 1993, Paper 45.3, pp. 1031-1040.
<i>me</i>			Zacharia, N. et al, "Decompression of Test Data Using Variable-Length Seed LFSRs," IEEE 1995, 426-433.
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				Docket: 1011-54375		App: 09/620,021	
				Applicant: Rajski et al.			
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Pmc		6,385,750	May, 2002	Kapur et al.			
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		Number	Date	Country	Class	Sub	
OTHER DOCUMENTS							
Pmc			Mano, M. Morris, "Computer System Architectures," 2 nd Edition, Prentice-Hall, Inc., New Jersey, 1982.				
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